 ·				SHEET 1 OF 1	
FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRONATEDYS. 0794VIC	APPLICATION NO. Unknown		
	DISCLOSURE STATEMENT	<u> </u>			
<u>į</u>		APPLICANT Gonzaiez et al.		•	
(USE SEVERA	L SHEETS IF NECESSARY)	FIUNG DATE Herewith	GROUP		

U.S. PATENT DOCUMENTS						
EXAMINER IMITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
411	4,627,153	12/9/86	Masuoka			
	4,651,406	3/24/87	Shimizu et al.			
	4,957,878	9/18/90	Lowrey et al.			
	4,675,982	6/30/87	Noble, Jr. et al.			
	5,057,449	10/15/91	Lowrey et al.			_
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	5,358,894	10/25/94	Fazan et al.			
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	5,376,593	12/27/94	Sandhu et al.	\vdash		
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	5,405,791	4/11/95	Ahmad et al.	ļ		
	5,407,870	4/18/95	Okada et al.			
	5,463,234	10/31/95	Toriumi et al.			·····
	5,502,009	3/26/96	Lin			··
-1	5,668,035	9/16/97	Fang et al.			
	5,863,819	1/26/99	Gonzalez			
1/	5,966,618	10/12/99	Sun et al.			<u> </u>
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EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
A.A.	S. Shimizu, et al., "Impact of Surface Proximity Gettering and Nitrided Oxide Side-Wall Spacer by Nitrogen Implantation on Sub-Quarter Micron CMOS LDD FETs," IEDM 1995, pp. 859-862

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EXAMINER John for	DATE CONSIDERED	6/11		19
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHIN CONFORMANCE AND NOT CONSIDERED, INCLUD	ETHER OR NOT CITATION IS IN CONFORMANCE WITH MPE E COPY OF THIS FORM WITH NEXT COMMUNICATION TO A	EP 609; ØRAW APPLICANT.	LINE	THROUGH CITATION IF NOT

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	FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY, DOCKET NO. MICRON.079DV1 C		APPLICATION NO.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICANT Gonzalez et el.			
	(USE SEVERAL	. SHEETS IF NECESSARY)	FILING DATE Herewith		GROUP Unknown

U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)		
PI	6,033,998	03/07/00	Aronowitz et al.		(03/09/98		
1	6,037,224	03/14/00	Buller et al.			05/02/97		
V	6,110,842	08/29/00	Okuno et al.			04/22/98		

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DATE CONSIDERED

EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 809; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.